

Monday September 4<sup>th</sup>, 2006

**ATMEL & ST Microelectronics Forum**

**15:00 – 18:15 Forum organized by ATMEL & ST Microelectronics**

**Title:** Test and Industrialization of nowadays SoCs: Orientations and challenges

**Chairs:** **L. BEN AMMAR** – ATMEL – France

**L. BOUZAIDA** – STMicroelectronics – Tunisia

**15:00 – 15:45** State of the Art and Future Challenges in Embedded RAM Memory Testing

**Speaker:** **S. HAMDIOUI** – Delft University – The Netherlands

**15:45 – 16:30** Test and Industrialization Challenges of Memory Dominated SoCs

**Speakers:** **L. BEN AMMAR** and **J. M. DAGA** – ATMEL – France

**16:30 – 16:45** **Coffee Break**

**16:45 – 17:30** Built in Test and Diagnosis Techniques for Logic circuits

**Speakers:** **L. BOUZAIDA** and **W. MAROUFI** – STMicroelectronics – Tunisia

**17:30 – 18:15** State of the Art and Future Challenges in Analog Test

**Speakers:** **S. BERNARD** and **M. RENOVELL** – LIRMM – France